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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	203
Number of Gates	48000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	256-LBGA
Supplier Device Package	256-FPBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx32a-2fgg256i

Power-Up/Down and Hot Swapping

SX-A I/Os are configured to be hot-swappable, with the exception of 3.3 V PCI. During power-up/down (or partial up/down), all I/Os are tristated. V_{CCA} and V_{CCI} do not have to be stable during power-up/down, and can be powered up/down in any order. When the SX-A device is plugged into an electrically active system, the device will not degrade the reliability of or cause damage to the host system. The device's output pins are driven to a high impedance state until normal chip operating conditions are reached. Table 1-4 summarizes the V_{CCA} voltage at which the I/Os behave according to the user's design for an SX-A device at room temperature for various ramp-up rates. The data reported assumes a linear ramp-up profile to 2.5 V. For more information on power-up and hot-swapping, refer to the application note, *Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications*.

Table 1-2 • **I/O Features**

Function	Description
Input Buffer Threshold Selections	• 5 V: PCI, TTL • 3.3 V: PCI, LVTTL • 2.5 V: LVCMOS2 (commercial only)
Flexible Output Driver	• 5 V: PCI, TTL • 3.3 V: PCI, LVTTL • 2.5 V: LVCMOS2 (commercial only)
Output Buffer	"Hot-Swap" Capability (3.3 V PCI is not hot swappable) • I/O on an unpowered device does not sink current • Can be used for "cold-sparing" Selectable on an individual I/O basis Individually selectable slew rate; high slew or low slew (The default is high slew rate). The slew is only affected on the falling edge of an output. Rising edges of outputs are not affected.
Power-Up	Individually selectable pull-ups and pull-downs during power-up (default is to power-up in tristate) Enables deterministic power-up of device V_{CCA} and V_{CCI} can be powered in any order

Table 1-3 • **I/O Characteristics for All I/O Configurations**

	Hot Swappable	Slew Rate Control	Power-Up Resistor
TTL, LVTTL, LVCMOS2	Yes	Yes. Only affects falling edges of outputs	Pull-up or pull-down
3.3 V PCI	No	No. High slew rate only	Pull-up or pull-down
5 V PCI	Yes	No. High slew rate only	Pull-up or pull-down

Table 1-4 • **Power-Up Time at which I/Os Become Active**

Supply Ramp Rate	0.25 V/µs	0.025 V/µs	5 V/ms	2.5 V/ms	0.5 V/ms	0.25 V/ms	0.1 V/ms	0.025 V/ms
Units	**µs**	**µs**	**ms**	**ms**	**ms**	**ms**	**ms**	**ms**
A54SX08A	10	96	0.34	0.65	2.7	5.4	12.9	50.8
A54SX16A	10	100	0.36	0.62	2.5	4.7	11.0	41.6
A54SX32A	10	100	0.46	0.74	2.8	5.2	12.1	47.2
A54SX72A	10	100	0.41	0.67	2.6	5.0	12.1	47.2

Boundary-Scan Testing (BST)

All SX-A devices are IEEE 1149.1 compliant and offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. The BST function is controlled through the special JTAG pins (TMS, TDI, TCK, TDO, and TRST). The functionality of the JTAG pins is defined by two available modes: Dedicated and Flexible. TMS cannot be employed as a user I/O in either mode.

Dedicated Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, the user must reserve the JTAG pins in Actel's Designer software. Reserve the JTAG pins by checking the **Reserve JTAG** box in the Device Selection Wizard (Figure 1-12).

The default for the software is Flexible mode; all boxes are unchecked. Table 1-5 lists the definitions of the options in the Device Selection Wizard.

Figure 1-12 • **Device Selection Wizard**

Table 1-5 • **Reserve Pin Definitions**

Pin	Function
Reserve JTAG	Keeps pins from being used and changes the behavior of JTAG pins (no pull-up on TMS)
Reserve JTAG Test Reset	Regular I/O or JTAG reset with an internal pull-up
Reserve Probe	Keeps pins from being used or regular I/O

Flexible Mode

In Flexible mode, TDI, TCK, and TDO may be employed as either user I/Os or as JTAG input pins. The internal resistors on the TMS and TDI pins are not present in flexible JTAG mode.

To select the Flexible mode, uncheck the **Reserve JTAG** box in the Device Selection Wizard dialog in the Actel Designer software. In Flexible mode, TDI, TCK, and TDO pins may function as user I/Os or BST pins. The functionality is controlled by the BST Test Access Port (TAP) controller. The TAP controller receives two control inputs, TMS and TCK. Upon power-up, the TAP controller enters the Test-Logic-Reset state. In this state, TDI, TCK, and TDO function as user I/Os. The TDI, TCK, and TDO are transformed from user I/Os into BST pins when a rising edge on TCK is detected while TMS is at logic low. To return to Test-Logic Reset state, TMS must be high for at least five TCK cycles. **An external 10 k pull-up resistor to V_{CCI} should be placed on the TMS pin to pull it High by default.**

Table 1-6 describes the different configuration requirements of BST pins and their functionality in different modes.

Table 1-6 • **Boundary-Scan Pin Configurations and Functions**

Mode	Designer "Reserve JTAG" Selection	TAP Controller State
Dedicated (JTAG)	Checked	Any
Flexible (User I/O)	Unchecked	Test-Logic-Reset
Flexible (JTAG)	Unchecked	Any EXCEPT Test-Logic-Reset

TRST Pin

The TRST pin functions as a dedicated Boundary-Scan Reset pin when the **Reserve JTAG Test Reset** option is selected as shown in Figure 1-12. An internal pull-up resistor is permanently enabled on the TRST pin in this mode. Actel recommends connecting this pin to ground in normal operation to keep the JTAG state controller in the Test-Logic-Reset state. When JTAG is being used, it can be left floating or can be driven high.

When the **Reserve JTAG Test Reset** option is not selected, this pin will function as a regular I/O. If unused as an I/O in the design, it will be configured as a tristated output.

SX-A Probe Circuit Control Pins

SX-A devices contain internal probing circuitry that provides built-in access to every node in a design, enabling 100% real-time observation and analysis of a device's internal logic nodes without design iteration. The probe circuitry is accessed by Silicon Explorer II, an easy to use, integrated verification and logic analysis tool that can sample data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

The Silicon Explorer II tool uses the boundary-scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-13 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

In order to preserve device probing capabilities, users should avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, critical input signals through these pins are not available. In addition, the security fuse must not be programmed to preserve probing capabilities. Actel recommends that you use a 70 Ω series termination resistor on every probe connector (TDI, TCK, TMS, TDO, PRA, PRB). The 70 Ω series termination is used to prevent data transmission corruption during probing and reading back the checksum.

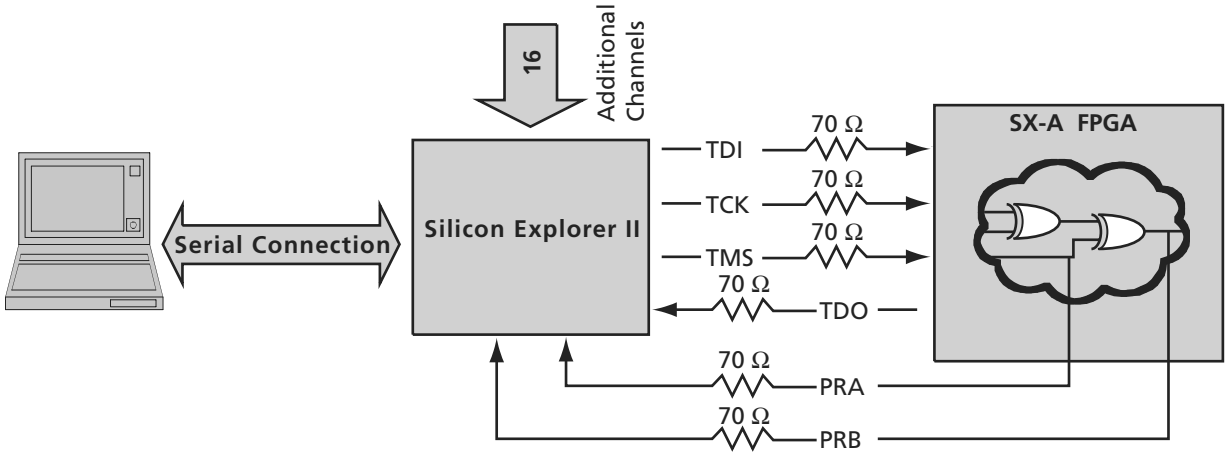

Figure 1-13 • **Probe Setup**

Power Dissipation

A critical element of system reliability is the ability of electronic devices to safely dissipate the heat generated during operation. The thermal characteristics of a circuit depend on the device and package used, the operating temperature, the operating current, and the system's ability to dissipate heat.

A complete power evaluation should be performed early in the design process to help identify potential heat-related problems in the system and to prevent the system from exceeding the device's maximum allowed junction temperature.

The actual power dissipated by most applications is significantly lower than the power the package can dissipate. However, a thermal analysis should be performed for all projects. To perform a power evaluation, follow these steps:

1. Estimate the power consumption of the application.
2. Calculate the maximum power allowed for the device and package.
3. Compare the estimated power and maximum power values.

Estimating Power Dissipation

The total power dissipation for the SX-A family is the sum of the DC power dissipation and the AC power dissipation:

$$P_{Total} = P_{DC} + P_{AC}$$

EQ 2-5

DC Power Dissipation

The power due to standby current is typically a small component of the overall power. An estimation of DC power dissipation under typical conditions is given by:

$$P_{DC} = I_{Standby} * V_{CCA}$$

EQ 2-6

Note: For other combinations of temperature and voltage settings, refer to the *eX, SX-A and RT54SX-S Power Calculator*.

AC Power Dissipation

The power dissipation of the SX-A family is usually dominated by the dynamic power dissipation. Dynamic power dissipation is a function of frequency, equivalent capacitance, and power supply voltage. The AC power dissipation is defined as follows:

$$P_{AC} = P_{C\text{-cells}} + P_{R\text{-cells}} + P_{CLKA} + P_{CLKB} + P_{HCLK} + P_{Output\ Buffer} + P_{Input\ Buffer}$$

EQ 2-7

or:

$$P_{AC} = V_{CCA}^2 * [(m * C_{EQCM} * fm)_{C\text{-cells}} + (m * C_{EQSM} * fm)_{R\text{-cells}} + (n * C_{EQI} * f_n)_{Input\ Buffer} + (p * (C_{EQO} + C_L) * f_p)_{Output\ Buffer} + (0.5 * (q_1 * C_{EQCR} * f_{q1}) + (r_1 * f_{q1}))_{CLKA} + (0.5 * (q_2 * C_{EQCR} * f_{q2}) + (r_2 * f_{q2}))_{CLKB} + (0.5 * (s_1 * C_{EQHV} * f_{s1}) + (C_{EQHF} * f_{s1}))_{HCLK}]$$

EQ 2-8

Where:

C_{EQCM} = Equivalent capacitance of combinatorial modules (C-cells) in pF

C_{EQSM} = Equivalent capacitance of sequential modules (R-Cells) in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of CLKA/B in pF

C_{EQHV} = Variable capacitance of HCLK in pF

C_{EQHF} = Fixed capacitance of HCLK in pF

C_{L} = Output lead capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average CLKA rate in MHz

f_{q2} = Average CLKB rate in MHz

f_{s1} = Average HCLK rate in MHz

m = Number of logic modules switching at fm

n = Number of input buffers switching at fn

p = Number of output buffers switching at fp

q_1 = Number of clock loads on CLKA

q_2 = Number of clock loads on CLKB

r_1 = Fixed capacitance due to CLKA

r_2 = Fixed capacitance due to CLKB

s_1 = Number of clock loads on HCLK

x = Number of I/Os at logic low

y = Number of I/Os at logic high

Table 2-11 • **CEQ Values for SX-A Devices**

	A54SX08A	**A54SX16A**	**A54SX32A**	**A54SX72A**
Combinatorial modules (C_{EQCM})	1.70 pF	2.00 pF	2.00 pF	1.80 pF
Sequential modules (C_{EQCM})	1.50 pF	1.50 pF	1.30 pF	1.50 pF
Input buffers (C_{EQI})	1.30 pF	1.30 pF	1.30 pF	1.30 pF
Output buffers (C_{EQO})	7.40 pF	7.40 pF	7.40 pF	7.40 pF
Routed array clocks (C_{EQCR})	1.05 pF	1.05 pF	1.05 pF	1.05 pF
Dedicated array clocks – variable (C_{EQHV})	0.85 pF	0.85 pF	0.85 pF	0.85 pF
Dedicated array clocks – fixed (C_{EQHF})	30.00 pF	55.00 pF	110.00 pF	240.00 pF
Routed array clock A (r_1)	35.00 pF	50.00 pF	90.00 pF	310.00 pF

Guidelines for Estimating Power

The following guidelines are meant to represent worst-case scenarios; they can be generally used to predict the upper limits of power dissipation:

Logic Modules (m) = 20% of modules

Inputs Switching (n) = Number inputs/4

Outputs Switching (p) = Number of outputs/4

CLKA Loads (q1) = 20% of R-cells

CLKB Loads (q2) = 20% of R-cells

Load Capacitance (CL) = 35 pF

Average Logic Module Switching Rate (fm) = f/10

Average Input Switching Rate (fn) =f/5

Average Output Switching Rate (fp) = f/10

Average CLKA Rate (fq1) = f/2

Average CLKB Rate (fq2) = f/2

Average HCLK Rate (fs1) = f

HCLK loads (s1) = 20% of R-cells

To assist customers in estimating the power dissipations of their designs, Actel has published the *eX, SX-A and RT54SX-S Power Calculator* worksheet.

Timing Characteristics

Timing characteristics for SX-A devices fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all SX-A family members. Internal routing delays are device-dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design are complete. The timing characteristics listed in this datasheet represent sample timing numbers of the SX-A devices. Design-specific delay values may be determined by using Timer or performing simulation after successful place-and-route with the Designer software.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6 percent of the nets in a design may be designated as critical, while 90 percent of the nets in a design are typical.

Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three to five antifuse connections. This increases capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 8.4 ns delay. This additional delay is represented statistically in higher fanout routing delays.

Timing Derating

SX-A devices are manufactured with a CMOS process. Therefore, device performance varies according to temperature, voltage, and process changes. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

Temperature and Voltage Derating Factors

Table 2-13 • **Temperature and Voltage Derating Factors (Normalized to Worst-Case Commercial, T_J = 70°C, V_{CCA} = 2.25 V)**

	Junction Temperature (T_J)						
V_{CCA}	**–55°C**	**–40°C**	**0°C**	**25°C**	**70°C**	**85°C**	**125°C**
2.250 V	0.79	0.80	0.87	0.89	1.00	1.04	1.14
2.500 V	0.74	0.75	0.82	0.83	0.94	0.97	1.07
2.750 V	0.68	0.69	0.75	0.77	0.87	0.90	0.99

Timing Characteristics

Table 2-14 • **A54SX08A Timing Characteristics (Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)**

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays[1]										
t_{PD}	Internal Array Module		0.9		1.1		1.2		1.7	ns
Predicted Routing Delays[2]										
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.4		0.6	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.4		0.5		0.6	ns
t_{RD2}	FO = 2 Routing Delay		0.5		0.5		0.6		0.8	ns
t_{RD3}	FO = 3 Routing Delay		0.6		0.7		0.8		1.1	ns
t_{RD4}	FO = 4 Routing Delay		0.8		0.9		1		1.4	ns
t_{RD8}	FO = 8 Routing Delay		1.4		1.5		1.8		2.5	ns
t_{RD12}	FO = 12 Routing Delay		2		2.2		2.6		3.6	ns
R-Cell Timing										
t_{RCO}	Sequential Clock-to-Q		0.7		0.8		0.9		1.3	ns
t_{CLR}	Asynchronous Clear-to-Q		0.6		0.6		0.8		1.0	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.7		0.7		0.9		1.2	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.2		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.4		1.5		1.8		2.5		ns
$t_{RECASYN}$	Asynchronous Recovery Time	0.4		0.4		0.5		0.7		ns
t_{HASYN}	Asynchronous Hold Time	0.3		0.3		0.4		0.6		ns
t_{MPW}	Clock Pulse Width	1.6		1.8		2.1		2.9		ns
Input Module Propagation Delays										
t_{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.8		0.9		1.0		1.4	ns
t_{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		1.0		1.2		1.4		1.9	ns
t_{INYH}	Input Data Pad to Y High 3.3 V PCI		0.6		0.6		0.7		1.0	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.7		0.8		0.9		1.3	ns
t_{INYH}	Input Data Pad to Y High 3.3 V LVTTL		0.7		0.7		0.9		1.2	ns
t_{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		1.0		1.1		1.3		1.8	ns

Notes:

1. *For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} , t_{RCO} + t_{RD1} + t_{PDn} , or t_{PD1} + t_{RD1} + t_{SUD} , whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*

Table 2-18 • **A54SX08A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 2.3 V, T_J = 70°C)**

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing[1,2]										
t_{DLH}	Data-to-Pad Low to High		3.9		4.4		5.2		7.2	ns
t_{DHL}	Data-to-Pad High to Low		3.0		3.4		3.9		5.5	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		13.3		15.1		17.7		24.8	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.8		3.2		3.7		5.2	ns
t_{ENZLS}	Data-to-Pad, Z to L—low slew		13.7		15.5		18.2		25.5	ns
t_{ENZH}	Enable-to-Pad, Z to H		3.9		4.4		5.2		7.2	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.5		2.8		3.3		4.7	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.0		3.4		3.9		5.5	ns
d_{TLH}[3]	Delta Low to High		0.037		0.043		0.051		0.071	ns/pF
d_{THL}[3]	Delta High to Low		0.017		0.023		0.023		0.037	ns/pF
d_{THLS}[3]	Delta High to Low—low slew		0.06		0.071		0.086		0.117	ns/pF

Note:

1. *Delays based on 35 pF loading.*
2. *The equivalent I/O Attribute Editor settings for 2.5 V LVCMOS is 2.5 V LVTTL in the software.*
3. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-20 • **A54SX08A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)**

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing[1]										
t_{DLH}	Data-to-Pad Low to High		2.4		2.8		3.2		4.5	ns
t_{DHL}	Data-to-Pad High to Low		3.2		3.6		4.2		5.9	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.5		1.7		2.0		2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.2		4.5	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.5		3.9		4.6		6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.2		3.6		4.2		5.9	ns
d_{TLH}[2]	Delta Low to High		0.016		0.02		0.022		0.032	ns/pF
d_{THL}[2]	Delta High to Low		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Output Module Timing[3]										
t_{DLH}	Data-to-Pad Low to High		2.4		2.8		3.2		4.5	ns
t_{DHL}	Data-to-Pad High to Low		3.2		3.6		4.2		5.9	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		7.6		8.6		10.1		14.2	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.4		2.7		3.2		4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		8.4		9.5		11.0		15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.2		4.5	ns
t_{ENLZ}	Enable-to-Pad, L to Z		4.2		4.7		5.6		7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z		3.2		3.6		4.2		5.9	ns
d_{TLH}	Delta Low to High		0.017		0.017		0.023		0.031	ns/pF
d_{THL}	Delta High to Low		0.029		0.031		0.037		0.051	ns/pF
d_{THLS}	Delta High to Low—low slew		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. *Delays based on 50 pF loading.*
2. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})$ / $(C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
3. *Delays based on 35 pF loading.*

Table 2-25 • **A54SX16A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 2.25 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing [2, 3]												
t_{DLH}	Data-to-Pad Low to High		3.4		3.9		4.5		5.2		7.3	ns
t_{DHL}	Data-to-Pad High to Low		2.6		3.0		3.3		3.9		5.5	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		11.6		13.4		15.2		17.9		25.0	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.4		2.8		3.2		3.7		5.2	ns
t_{ENZLS}	Data-to-Pad, Z to L—low slew		11.8		13.7		15.5		18.2		25.5	ns
t_{ENZH}	Enable-to-Pad, Z to H		3.4		3.9		4.5		5.2		7.3	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.1		2.5		2.8		3.3		4.7	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.6		3.0		3.3		3.9		5.5	ns
d_{TLH}[4]	Delta Low to High		0.031		0.037		0.043		0.051		0.071	ns/pF
d_{THL}[4]	Delta High to Low		0.017		0.017		0.023		0.023		0.037	ns/pF
d_{THLS}[4]	Delta High to Low—low slew		0.057		0.06		0.071		0.086		0.117	ns/pF

Note:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 35 pF loading.*
3. *The equivalent IO Attribute settings for 2.5 V LVCMOS is 2.5 V LVTTL in the software.*
4. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-26 • **A54SX16A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
3.3 V PCI Output Module Timing[2]												
t_{DLH}	Data-to-Pad Low to High		2.0		2.3		2.6		3.1		4.3	ns
t_{DHL}	Data-to-Pad High to Low		2.2		2.5		2.8		3.3		4.6	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.4		1.7		1.9		2.2		3.1	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.0		2.3		2.6		3.1		4.3	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.5		2.8		3.2		3.8		5.3	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.2		2.5		2.8		3.3		4.6	ns
d_{TLH}[3]	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d_{THL}[3]	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
3.3 V LVTTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad Low to High		2.8		3.2		3.6		4.3		6.0	ns
t_{DHL}	Data-to-Pad High to Low		2.7		3.1		3.5		4.1		5.7	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		9.5		10.9		12.4		14.6		20.4	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.2		2.6		2.9		3.4		4.8	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		15.8		18.9		21.3		25.4		34.9	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.8		3.2		3.6		4.3		6.0	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.9		3.3		3.7		4.4		6.2	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.7		3.1		3.5		4.1		5.7	ns
d_{TLH}[3]	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d_{THL}[3]	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
d_{THLS}[3]	Delta High to Low—low slew		0.053		0.053		0.067		0.073		0.107	ns/pF

Notes:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 10 pF loading and 25 Ω resistance.*
3. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. *Delays based on 35 pF loading.*

Table 2-27 • **A54SX16A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)**

Parameter	Description	–3 Speed[1]		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing[2]												
t_{DLH}	Data-to-Pad Low to High		2.2		2.5		2.8		3.3		4.6	ns
t_{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns
t_{ENZL}	Enable-to-Pad, Z to L		1.3		1.5		1.7		2.0		2.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		2.2		2.5		2.8		3.3		4.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.0		3.5		3.9		4.6		6.4	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.8		3.2		3.6		4.2		5.9	ns
d_{TLH}[3]	Delta Low to High		0.016		0.016		0.02		0.022		0.032	ns/pF
d_{THL}[3]	Delta High to Low		0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Output Module Timing[4]												
t_{DLH}	Data-to-Pad Low to High		2.2		2.5		2.8		3.3		4.6	ns
t_{DHL}	Data-to-Pad High to Low		2.8		3.2		3.6		4.2		5.9	ns
t_{DHLS}	Data-to-Pad High to Low—low slew		6.7		7.7		8.7		10.2		14.3	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.1		2.4		2.7		3.2		4.5	ns
t_{ENZLS}	Enable-to-Pad, Z to L—low slew		7.4		8.4		9.5		11.0		15.4	ns
t_{ENZH}	Enable-to-Pad, Z to H		1.9		2.2		2.5		2.9		4.1	ns
t_{ENLZ}	Enable-to-Pad, L to Z		3.6		4.2		4.7		5.6		7.8	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.5		2.9		3.3		3.9		5.4	ns
d_{TLH}[3]	Delta Low to High		0.014		0.017		0.017		0.023		0.031	ns/pF
d_{THL}[3]	Delta High to Low		0.023		0.029		0.031		0.037		0.051	ns/pF
d_{THLS}[3]	Delta High to Low—low slew		0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. *All –3 speed grades have been discontinued.*
2. *Delays based on 50 pF loading.*
3. *To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:*
   Slew Rate [V/ns] = $(0.1*V_{CCI} – 0.9*V_{CCI})/ (C_{load} * d_{T[LH|HL|HLS]})$
   where C_{load} is the load capacitance driven by the I/O in pF
   $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. *Delays based on 35 pF loading.*

Table 2-38 • **A54SX72A Timing Characteristics (Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 4.75 V, T_J = 70°C)**

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t_{HCKH}	Input Low to High (Pad to R-cell Input)		1.6		1.8		2.1		2.4		3.8	ns
t_{HCKL}	Input High to Low (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.8	ns
t_{HPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{HPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{HCKSW}	Maximum Skew		1.4		1.6		1.8		2.1		3.3	ns
t_{HP}	Minimum Period	3.0		3.4		4.0		4.6		6.4		ns
f_{HMAX}	Maximum Frequency		333		294		250		217		156	MHz
Routed Array Clock Networks												
t_{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.3		2.6		3.0		3.5		4.9	ns
t_{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.8		3.2		3.6		4.3		6.0	ns
t_{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.5		2.9		3.2		3.8		5.3	ns
t_{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t_{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.6		3.0		3.4		3.9		5.5	ns
t_{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		3.2		3.6		4.1		4.8		6.8	ns
t_{RPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{RPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{RCKSW}	Maximum Skew (Light Load)		1.9		2.2		2.5		3.0		4.1	ns
t_{RCKSW}	Maximum Skew (50% Load)		1.9		2.2		2.5		3.0		4.1	ns
t_{RCKSW}	Maximum Skew (100% Load)		1.9		2.2		2.5		3.0		4.1	ns
Quadrant Array Clock Networks												
t_{QCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.6	ns
t_{QCHKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.3		1.4		1.6		1.9		2.7	ns
t_{QCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.4		1.6		1.8		2.1		3.0	ns
t_{QCHKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.4		1.7		1.9		2.2		3.1	ns

Note: **All –3 speed grades have been discontinued.*

100-TQFP			
Pin Number	**A54SX08A Function**	**A54SX16A Function**	**A54SX32A Function**
71	I/O	I/O	I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	I/O	I/O	I/O
78	I/O	I/O	I/O
79	I/O	I/O	I/O
80	I/O	I/O	I/O
81	I/O	I/O	I/O
82	V_{CCI}	V_{CCI}	V_{CCI}
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	I/O	I/O	I/O
86	I/O	I/O	I/O
87	CLKA	CLKA	CLKA
88	CLKB	CLKB	CLKB
89	NC	NC	NC
90	V_{CCA}	V_{CCA}	V_{CCA}
91	GND	GND	GND
92	PRA, I/O	PRA, I/O	PRA, I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	I/O	I/O	I/O
97	I/O	I/O	I/O
98	I/O	I/O	I/O
99	I/O	I/O	I/O
100	TCK, I/O	TCK, I/O	TCK, I/O

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	I/O	I/O	I/O
78	I/O	I/O	I/O
79	V_{CCA}	V_{CCA}	V_{CCA}
80	V_{CCI}	V_{CCI}	V_{CCI}
81	GND	GND	GND
82	I/O	I/O	I/O
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	I/O	I/O	I/O
86	I/O	I/O	I/O
87	I/O	I/O	I/O
88	I/O	I/O	I/O
89	V_{CCA}	V_{CCA}	V_{CCA}
90	NC	NC	NC
91	I/O	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	I/O	I/O	I/O
97	I/O	I/O	I/O
98	V_{CCA}	V_{CCA}	V_{CCA}
99	GND	GND	GND
100	I/O	I/O	I/O
101	GND	GND	GND
102	V_{CCI}	V_{CCI}	V_{CCI}
103	I/O	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	I/O	I/O	I/O
107	I/O	I/O	I/O
108	I/O	I/O	I/O
109	GND	GND	GND
110	I/O	I/O	I/O

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
111	I/O	I/O	I/O
112	I/O	I/O	I/O
113	I/O	I/O	I/O
114	I/O	I/O	I/O
115	V_{CCI}	V_{CCI}	V_{CCI}
116	I/O	I/O	I/O
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O
121	I/O	I/O	I/O
122	I/O	I/O	I/O
123	I/O	I/O	I/O
124	I/O	I/O	I/O
125	CLKA	CLKA	CLKA
126	CLKB	CLKB	CLKB
127	NC	NC	NC
128	GND	GND	GND
129	V_{CCA}	V_{CCA}	V_{CCA}
130	I/O	I/O	I/O
131	PRA, I/O	PRA, I/O	PRA, I/O
132	I/O	I/O	I/O
133	I/O	I/O	I/O
134	I/O	I/O	I/O
135	I/O	I/O	I/O
136	I/O	I/O	I/O
137	I/O	I/O	I/O
138	I/O	I/O	I/O
139	I/O	I/O	I/O
140	V_{CCI}	V_{CCI}	V_{CCI}
141	I/O	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	TCK, I/O	TCK, I/O	TCK, I/O

329-Pin PBGA	
Pin Number	**A54SX32A Function**
D11	V_{CCA}
D12	NC
D13	I/O
D14	I/O
D15	I/O
D16	I/O
D17	I/O
D18	I/O
D19	I/O
D20	I/O
D21	I/O
D22	I/O
D23	I/O
E1	V_{CCI}
E2	I/O
E3	I/O
E4	I/O
E20	I/O
E21	I/O
E22	I/O
E23	I/O
F1	I/O
F2	TMS
F3	I/O
F4	I/O
F20	I/O
F21	I/O
F22	I/O
F23	I/O
G1	I/O
G2	I/O
G3	I/O
G4	I/O
G20	I/O
G21	I/O
G22	I/O
G23	GND

329-Pin PBGA	
Pin Number	**A54SX32A Function**
H1	I/O
H2	I/O
H3	I/O
H4	I/O
H20	V_{CCA}
H21	I/O
H22	I/O
H23	I/O
J1	NC
J2	I/O
J3	I/O
J4	I/O
J20	I/O
J21	I/O
J22	I/O
J23	I/O
K1	I/O
K2	I/O
K3	I/O
K4	I/O
K10	GND
K11	GND
K12	GND
K13	GND
K14	GND
K20	I/O
K21	I/O
K22	I/O
K23	I/O
L1	I/O
L2	I/O
L3	I/O
L4	NC
L10	GND
L11	GND
L12	GND
L13	GND

329-Pin PBGA	
Pin Number	**A54SX32A Function**
L14	GND
L20	NC
L21	I/O
L22	I/O
L23	NC
M1	I/O
M2	I/O
M3	I/O
M4	V_{CCA}
M10	GND
M11	GND
M12	GND
M13	GND
M14	GND
M20	V_{CCA}
M21	I/O
M22	I/O
M23	V_{CCI}
N1	I/O
N2	TRST, I/O
N3	I/O
N4	I/O
N10	GND
N11	GND
N12	GND
N13	GND
N14	GND
N20	NC
N21	I/O
N22	I/O
N23	I/O
P1	I/O
P2	I/O
P3	I/O
P4	I/O
P10	GND
P11	GND

329-Pin PBGA	
Pin Number	**A54SX32A Function**
P12	GND
P13	GND
P14	GND
P20	I/O
P21	I/O
P22	I/O
P23	I/O
R1	I/O
R2	I/O
R3	I/O
R4	I/O
R20	I/O
R21	I/O
R22	I/O
R23	I/O
T1	I/O
T2	I/O
T3	I/O
T4	I/O
T20	I/O
T21	I/O
T22	I/O
T23	I/O
U1	I/O
U2	I/O
U3	V_{CCA}
U4	I/O
U20	I/O
U21	V_{CCA}
U22	I/O
U23	I/O
V1	V_{CCI}
V2	I/O
V3	I/O
V4	I/O
V20	I/O
V21	I/O

256-Pin FBGA

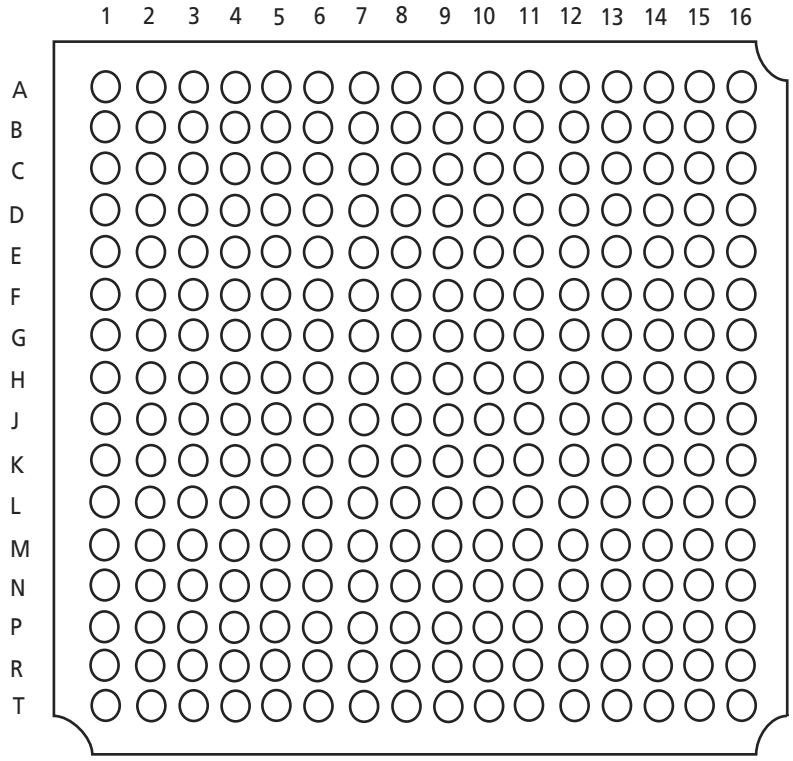

Figure 3-7 • **256-Pin FBGA (Top View)**

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.

256-Pin FBGA			
Pin Number	**A54SX16A Function**	**A54SX32A Function**	**A54SX72A Function**
E11	I/O	I/O	I/O
E12	I/O	I/O	I/O
E13	NC	I/O	I/O
E14	I/O	I/O	I/O
E15	I/O	I/O	I/O
E16	I/O	I/O	I/O
F1	I/O	I/O	I/O
F2	I/O	I/O	I/O
F3	I/O	I/O	I/O
F4	TMS	TMS	TMS
F5	I/O	I/O	I/O
F6	I/O	I/O	I/O
F7	V_{CCI}	V_{CCI}	V_{CCI}
F8	V_{CCI}	V_{CCI}	V_{CCI}
F9	V_{CCI}	V_{CCI}	V_{CCI}
F10	V_{CCI}	V_{CCI}	V_{CCI}
F11	I/O	I/O	I/O
F12	VCCA	VCCA	VCCA
F13	I/O	I/O	I/O
F14	I/O	I/O	I/O
F15	I/O	I/O	I/O
F16	I/O	I/O	I/O
G1	NC	I/O	I/O
G2	I/O	I/O	I/O
G3	NC	I/O	I/O
G4	I/O	I/O	I/O
G5	I/O	I/O	I/O
G6	V_{CCI}	V_{CCI}	V_{CCI}
G7	GND	GND	GND
G8	GND	GND	GND
G9	GND	GND	GND
G10	GND	GND	GND
G11	V_{CCI}	V_{CCI}	V_{CCI}
G12	I/O	I/O	I/O
G13	GND	GND	GND
G14	NC	I/O	I/O
G15	V_{CCA}	V_{CCA}	V_{CCA}

256-Pin FBGA			
Pin Number	**A54SX16A Function**	**A54SX32A Function**	**A54SX72A Function**
G16	I/O	I/O	I/O
H1	I/O	I/O	I/O
H2	I/O	I/O	I/O
H3	V_{CCA}	V_{CCA}	V_{CCA}
H4	TRST, I/O	TRST, I/O	TRST, I/O
H5	I/O	I/O	I/O
H6	V_{CCI}	V_{CCI}	V_{CCI}
H7	GND	GND	GND
H8	GND	GND	GND
H9	GND	GND	GND
H10	GND	GND	GND
H11	V_{CCI}	V_{CCI}	V_{CCI}
H12	I/O	I/O	I/O
H13	I/O	I/O	I/O
H14	I/O	I/O	I/O
H15	I/O	I/O	I/O
H16	NC	I/O	I/O
J1	NC	I/O	I/O
J2	NC	I/O	I/O
J3	NC	I/O	I/O
J4	I/O	I/O	I/O
J5	I/O	I/O	I/O
J6	V_{CCI}	V_{CCI}	V_{CCI}
J7	GND	GND	GND
J8	GND	GND	GND
J9	GND	GND	GND
J10	GND	GND	GND
J11	V_{CCI}	V_{CCI}	V_{CCI}
J12	I/O	I/O	I/O
J13	I/O	I/O	I/O
J14	I/O	I/O	I/O
J15	I/O	I/O	I/O
J16	I/O	I/O	I/O
K1	I/O	I/O	I/O
K2	I/O	I/O	I/O
K3	NC	I/O	I/O
K4	V_{CCA}	V_{CCA}	V_{CCA}

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
C19	I/O	I/O
C20	V_{CCI}	V_{CCI}
C21	I/O	I/O
C22	I/O	I/O
C23	I/O	I/O
C24	I/O	I/O
C25	NC*	I/O
C26	NC*	I/O
D1	NC*	I/O
D2	TMS	TMS
D3	I/O	I/O
D4	V_{CCI}	V_{CCI}
D5	NC*	I/O
D6	TCK, I/O	TCK, I/O
D7	I/O	I/O
D8	I/O	I/O
D9	I/O	I/O
D10	I/O	I/O
D11	I/O	I/O
D12	I/O	QCLKC
D13	I/O	I/O
D14	I/O	I/O
D15	I/O	I/O
D16	I/O	I/O
D17	I/O	I/O
D18	I/O	I/O
D19	I/O	I/O
D20	I/O	I/O
D21	V_{CCI}	V_{CCI}
D22	GND	GND
D23	I/O	I/O
D24	I/O	I/O
D25	NC*	I/O
D26	NC*	I/O
E1	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
E2	NC*	I/O
E3	I/O	I/O
E4	I/O	I/O
E5	GND	GND
E6	TDI, IO	TDI, IO
E7	I/O	I/O
E8	I/O	I/O
E9	I/O	I/O
E10	I/O	I/O
E11	I/O	I/O
E12	I/O	I/O
E13	V_{CCA}	V_{CCA}
E14	CLKB	CLKB
E15	I/O	I/O
E16	I/O	I/O
E17	I/O	I/O
E18	I/O	I/O
E19	I/O	I/O
E20	I/O	I/O
E21	I/O	I/O
E22	I/O	I/O
E23	I/O	I/O
E24	I/O	I/O
E25	V_{CCI}	V_{CCI}
E26	GND	GND
F1	V_{CCI}	V_{CCI}
F2	NC*	I/O
F3	NC*	I/O
F4	I/O	I/O
F5	I/O	I/O
F22	I/O	I/O
F23	I/O	I/O
F24	I/O	I/O
F25	I/O	I/O
F26	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
G1	NC*	I/O
G2	NC*	I/O
G3	NC*	I/O
G4	I/O	I/O
G5	I/O	I/O
G22	I/O	I/O
G23	V_{CCA}	V_{CCA}
G24	I/O	I/O
G25	NC*	I/O
G26	NC*	I/O
H1	NC*	I/O
H2	NC*	I/O
H3	I/O	I/O
H4	I/O	I/O
H5	I/O	I/O
H22	I/O	I/O
H23	I/O	I/O
H24	I/O	I/O
H25	NC*	I/O
H26	NC*	I/O
J1	NC*	I/O
J2	NC*	I/O
J3	I/O	I/O
J4	I/O	I/O
J5	I/O	I/O
J22	I/O	I/O
J23	I/O	I/O
J24	I/O	I/O
J25	V_{CCI}	V_{CCI}
J26	NC*	I/O
K1	I/O	I/O
K2	V_{CCI}	V_{CCI}
K3	I/O	I/O
K4	I/O	I/O
K5	V_{CCA}	V_{CCA}

Note: **These pins must be left floating on the A54SX32A device.*